Surface Texture Measuring Instrument

Operator-oriented Operation for the Workplace Compact Field Surface Measuring Instrument



SURFCOM 130A

LCD Panel Simplifies Operation

 Simply select the desired operation from the color LCD touch panel with a wide field of view or the reasonable monochrome LCD.

Highly Portable Compact Unit

• The unit is small enough for use at virtually any location.

Supports International Standard Analysis Parameters

Select the desired standard: JIS, ISO, DIN, ASME or CNOMO.

Satisfies European Directives for CE Marking







Simplified 16% rule automatic discrimination



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Customize Icons

The customize function can be used to create a special menu where only the icons that are used most frequently are displayed, substantially enhancing operational efficiency.



AI Function (patented)

The AI (artificial intelligence) function automatically selects the ideal cut-off value, measuring range and other conditions by simply entering the parameters and allowable values denoted on the machining drawing. This automates measurement.



Guidance Function

This function guides the user through the measuring procedures, enabling beginners to make measurements.



Memo Function

A short note or diagram can be entered with the touch pen and printed using the memo function.



Host of Analysis Functions

The unit incorporates 34 types of roughness parameters (Ra, Rz, Ry, Sm, S, tp, etc.) and 32 types of waviness parameters. The steps on electrical parts, film thickness, surface area and other items can be analyzed.



Tilt Correction Function

Six types of automatic tilt correction are provided: Linear, first half, latter half, both end, round surface and spline curve (patented).



Evaluation Range Setting (patented)

The waveform on the screen is enclosed by two cursors, allowing the desired evaluation range to be set and the parameters to be calculated.

PC Card Slot

Measuring conditions, measured result management or measured data can be output in binary and text format. This data can be easily read from the PC card slot on a personal computer. Storage of data on CF cards and other types of memory cards is possible to use.





Convenient Mode Select Function for System Manager/Operator

Outstanding Analysis Functions

Step Profile Evaluation

[Example Measurement] Hybrid IC



Can be used for hybrid IC, magnetic head, and other step measurement, film measurement, and surface area measurement.



R-Surface Correction





Ra Rz Pt *Rz.J

〈粗さ曲線〉

維倍加

載 日平 横倍率 縦目盛 横目盛

-



ガウシアン 400.0μm R面 300

0. 131μπ 0. 702μπ 2. 300μπ 2. 031μπ

10000 20 (AUTO) 1µm/ 10mm 500µm/ 10mm

MUMM

Options



Roll Foot E-MA-S62A Attachment for placing the drive unit on a roll shaped object for measurement Roll outer diameter: ϕ 60 mm or more



Battery Option Set E-MA-S65A For measuring and recording in a lo

For measuring and recording in a location where there is no power outlet available. Included items: AC adaptor, battery, charger



Pickup Holder for All-Orientations E-DH-S107A

For measuring surface roughness of slanted surfaces, vertical surfaces, ceiling surfaces, and other non-flat surfaces. Photograph shows unit with E-MA-S63A roll



PC card E-MU-S50B Provides storage for approximately 500 measurement conditions, or approximately 500 data measurements (100 text management items). Specifications: 64 MB

Pickup Holder for Horizontal Tracing E-DH-S17A

Attachment for horizontal tracing of items, such as a crankshaft, that have obstacles in the front and back in the measuring direction (using double-side straddling skid)



E-ST-S130A

The height and inclination of the drive unit can be adjusted in accordance with the size and shape of the object being measured. Table size: 410x200mm Maximum measuring height: 200mm

Specifications

Model		SURFCOM 130A
Measuring Range	X-axis (horizontal)	50mm
	Z-axis (vertical)	800μm (Measuring range/resolution: 800μm/10nm, 80μm/1nm, 8μm/0.1nm)
Straightness accuracy		0.3µm/50mm
Analysis items	Standards	Complies with JIS-2001, JIS-1994, JIS-1982, ISO-1997, ISO-1984, DIN-1990, ASME-1995, CNOMO
	Parameters	Ra, Rq, Ry, Rp, Rv, Rc, Rz, Rmax, Rt, Rz.J, R3z, Sm, S, R $\Delta a,$ R $\Delta q,$ R $\lambda a,$ R $\lambda q,$
		TILT A, Ir, Pc, Rsk, Rku, Rk, Rpk, Rvk, Mr1, Mr2, VO, K, tp, Rmr, tp2, Rmr2, R δ c,
		AVH, Hmax, Hmin, AREA, NCRX, R, Rx, AR, NR, CPM, SR, SAR
	Evaluation curves	Section profile curve, roughness curve, filtered waviness curve, filtered center line waviness curve, rolling circle waviness curve,
		rolling circle center line waviness curve, DIN4776 special curve, roughness motif curve, waviness motif curve, envelope waviness curve
	Surface Characteristics graphs	Bearing area curve, amplitude distribution (ADF) curve, power graph
	Tilt correction	Linear correction, round surface correction, first half correction, latter half correction, both end correction,
		spline curve correction (linear, round surface, and both end correction possible at arbitrary range)
Magnification	Vertical (Z-axis)	50, 100, 200, 500, 1K, 2K, 5K, 10K, 20K, 50K, 100K auto
	Horizontal (X-axis)	1, 2, 5, 10, 20, 50, 100, 200, 500, 1K, 2K, 5K, auto
Filter types		Standard filter (2RC), phase compensation filter (2RC), phase compensation filter (Gaussian)
Measuring Speed		0.3, 0.6, 1.5, 3mm/s (4 speeds)
Detector		Tip radius: 2μ m, Material: Diamond, Measuring force: 0.75mN
Special functions	AI Function	Al functions provides for easy procedures, enabling beginners to make measurements.
	Step analysis	Ideal for film thickness and surface area measurement of semiconductor parts.
	PC card	Data output as text file for transfer to a personal computer.
Standard accessories		Standard specimen (E-MC-S24B), recording paper (E-CH-S21A), touch pen (E-MA-S54A), instruction manual
Dimensions and	Power Source	AC100–240V ±10%, 50/60Hz, 30VA
weight	Installation dimensions	700 (W) ×300 (D) ×150 (H) mm
	Weight	8kg

* PC card (E-MU-S50B) and PC connection cable (E-SC-S288A) are options.



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Vight Software

- On-site SURFCOM surface analysis software
- · All the basic functions of TiMS program roughness analysis
- · Expanded roughness analysis functions for high-level analysis



· Data Transfer using an RS-232C interface (S130A, S480A, E35A) or PC card (S130A, S480A).



- · Data save to files
- Allows analysis of measured data to be performed on-site. Computer-based operation allows sharing of data with other computers.

TESCHART — Excel Converter

 Any parameter value obtained as measured results can be transferred via RS-232C data communication in real time to a cell in Microsoft Excel running on a computer connected to the S130A/S480A or HANDY SURF. (Waveform data cannot be transferred.)





